

The **next** circuits for a better life



Chip Design for Gravitational Wave Detectors

Alberto Gatti, Ciana Barretto and Filip Tavernier

KU LEUVEN



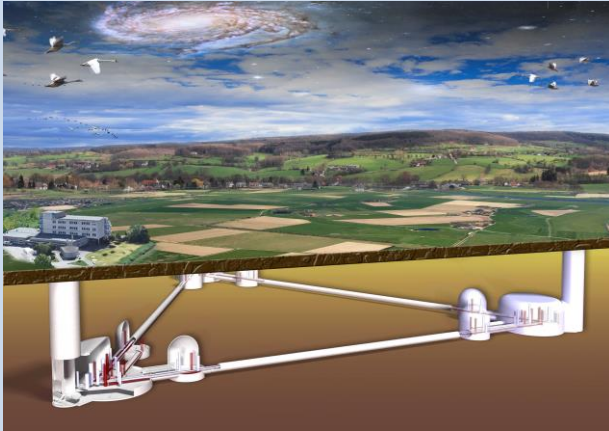
Introduction



- Integrated circuit and sensor design
- Two currently active projects for GW detectors:
 - Einstein Telescope (ET)
 - Laser Interferometer Space Antenna (LISA)
- Supervisor: Prof. Dr. Ir. Filip Tavernier

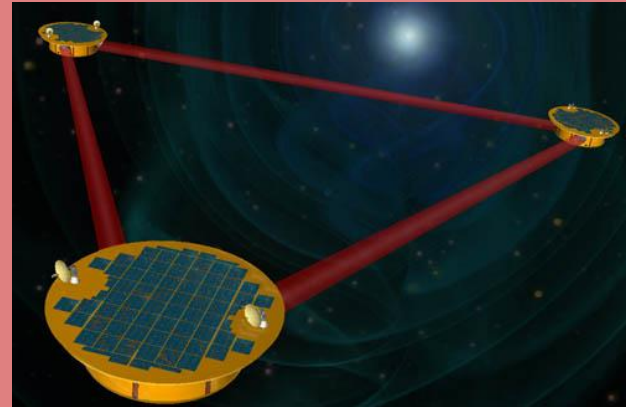
Two Different Design Cases

Cryo-CMOS circuits for ET cryogenic chambers



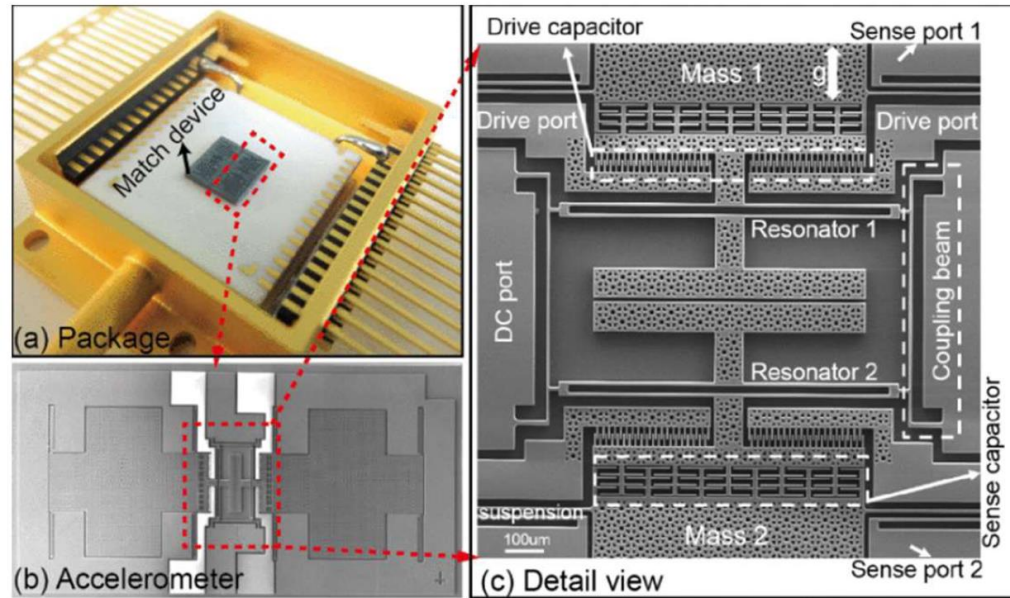
Deep-cryogenic environment

Optical Front End Electronics for LISA



Radiation exposure

Cryo-CMOS and sensors for ET



- Application: ultra-cold vibration control for the interferometer mirrors
- MEMS accelerometers with novel cryogenic CMOS signal conditioning integrated circuits

Why Custom Integrated Circuits?



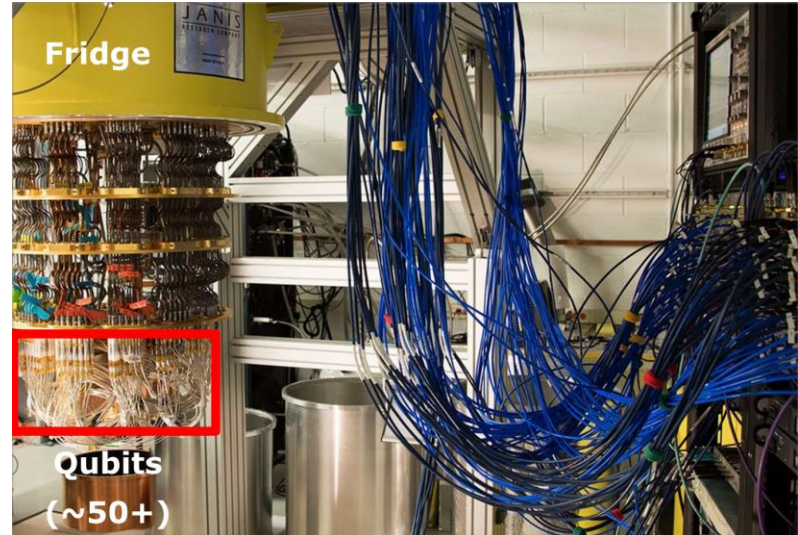
Main advantages:

- 😊 Tailored for the application
- 😊 VLSI integration
 - 😊 Less volume and cabling
- 😊 Less power
- 😊 Signal integrity
 - 😊 Amplification/conditioning close to sensor



Specific challenges:

- 😞 Extreme environments
- 😞 **Device modeling**



[J. C. Bardin et al., ISSCC 2019]

Compact Models for Circuit Simulation

Compact model \neq TCAD model!

- TCAD models are not fast enough

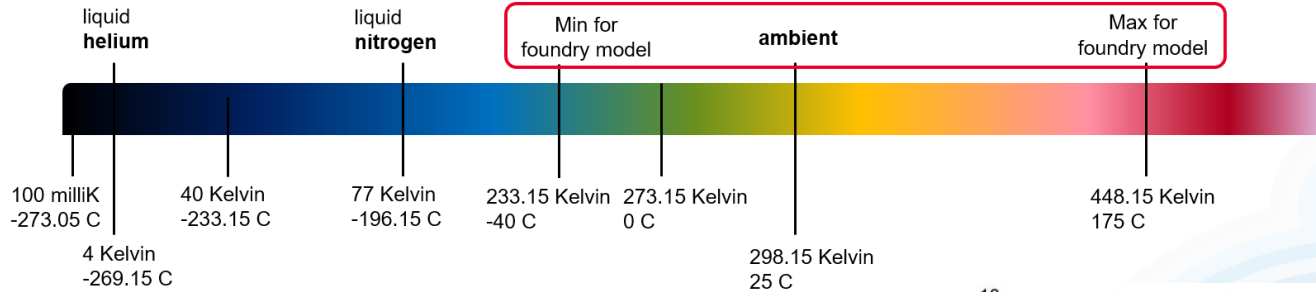
Compact models try to capture the electrical behavior of the device

- Generally not derived from the underlying physics

Model cards = set of device parameters

```
*****
* BSIM4.5.0 model card for p-type devices
*****
.model pch_svt.1 pmos ( level = 54
*****
*
* MODEL FLAG PARAMETERS
*****
+lmin = 2.59e-008      lmax = 2.51e-007      wmin = 'wmin_p_svt'
+wmax = 'wmax_p_svt'  version = 4.5          binunit = 1
+paramchk = 1         mobmod = 1              capmod = 2
+igcmod = 2           igbmod = 1              geomod = 0
+diomod = 1          rdsmod = 0              rbodymod = 0
+ргеomod = 0         rgatemod = 0           permod = 1
+acnqsmod = 0        trnqsmod = 0
*****
*
* GENERAL MODEL PARAMETERS
*****
+tnom = 25            tox = 'tox_p_svt'      toxp = 1.012e-009
+toxm = 'tox_p_svt'  dtox = 2.5e-010       epsrox = 3.9
+toxref = 1.2e-009  wmlt = 1              wint = 0
+lint = 4.1628e-011 ll = 0                wl = 0
+lln = 1            wln = 1                lw = 0
+ww = 0             lwn = 1                wwn = 1
+lw1 = 0           wwl = 0                xl = '0+dxlp_svt'
+xw = '0+dxwp_svt' dlc = 2.6887e-009      dwc = 0
+xpert = 0
*****
*
* DC PARAMETERS
*****
+vt0 = '-0.46149+dvthp_svt+sdvtp_svt+sigvtp_svt' k1 = 0.35256
+k1 = -0.0024567    k2 = 0.017398       k3 = 0.27044
+k3b = 0.07434     w0 = 1e-007          dvt0 = 0.52272
+dvt1 = 0.50091    dvt2 = -0.021065       dvt0w = 0.013
+dvt1w = 5984800  dvt2w = 0.05           dsub = 4.1202
```

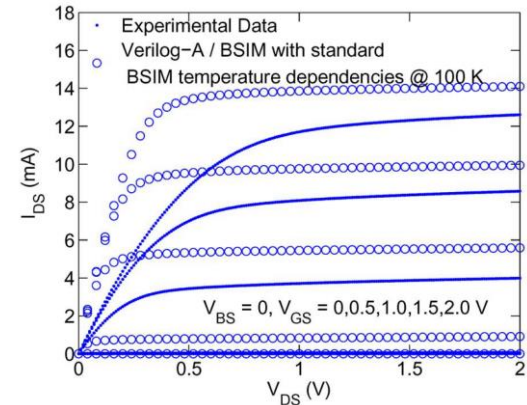
Deep-cryogenic device modeling for ET



☹ Compact models provided by foundries are unable to describe cryogenic behavior

☹ Cryogenic characterization and modeling are required

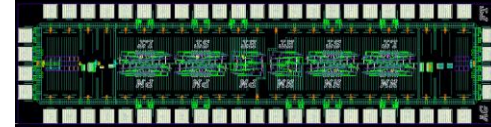
😊 T is very well regulated



[A. Akturk et al., Trans. El. Dev., 2010]

Cryo-CMOS Design Roadmap

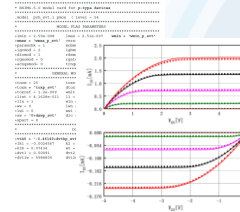
Design of test structures in different nanoscale CMOS technologies (supplied by foundries)



Characterization inside a cryostat and model parameter extraction



Editing of foundry models to enable cryogenic Integrated Circuit simulation

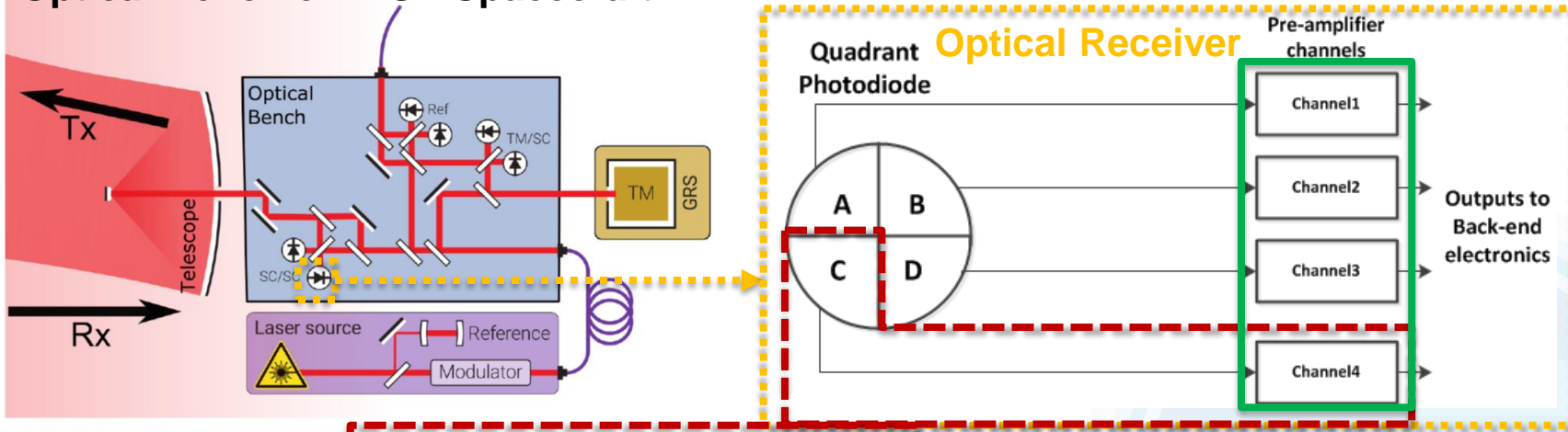


Design of cryogenic Application Specific Integrated Circuits (ASICs)



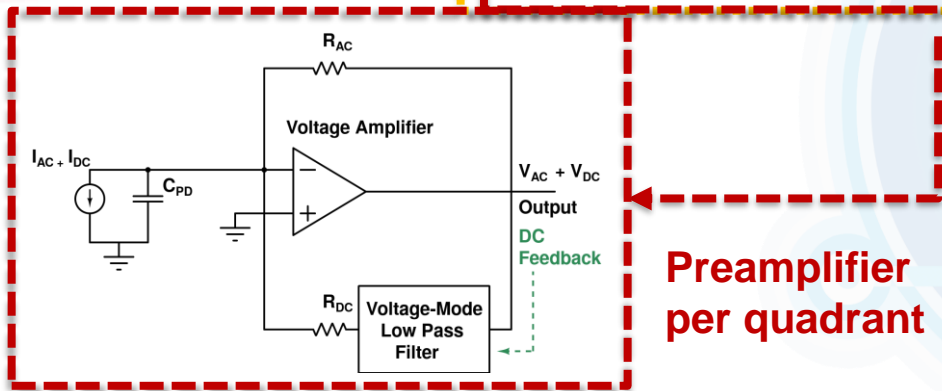
Optical Front-End Electronics (FEE) for LISA

Optical Bench on LISA Spacecraft



TM : Test Mass
SC : Spacecraft
GRS : Gravitational Sensor

ESA-L3-EST-INST-DD-001:December 2017

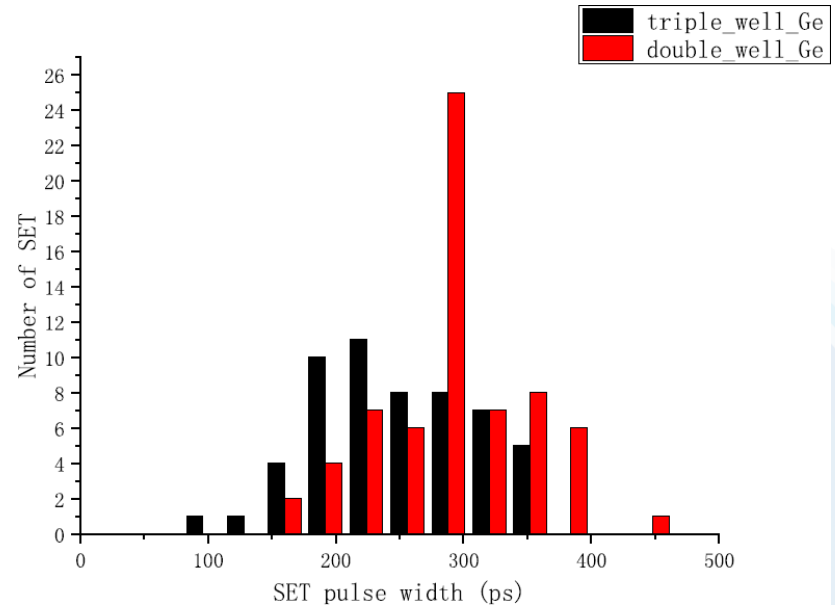


Preamplifier per quadrant

ASIC Optical FEE

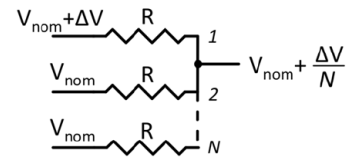
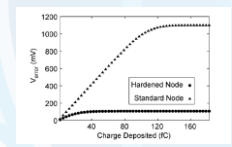
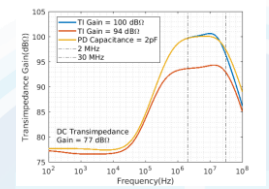
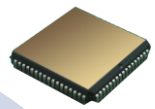
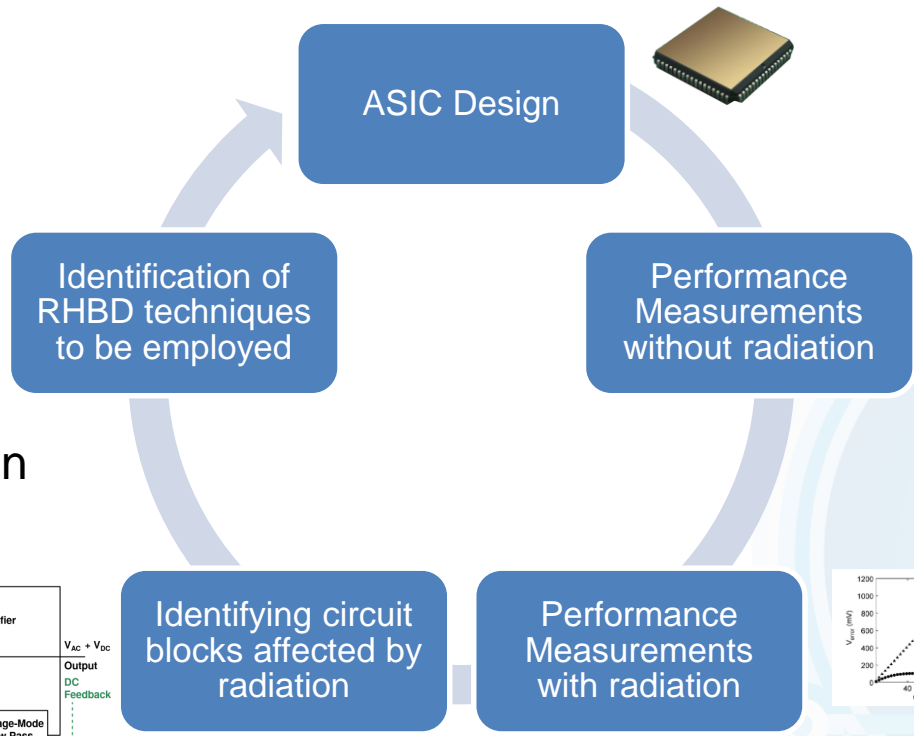
Radiation induced development challenges

- ❷ Insufficient modeling
- ❷ Absence of parameters needed to understand topology-based SET effects
- ❷ Radiation models for very high TID levels available which cause overdesign if used

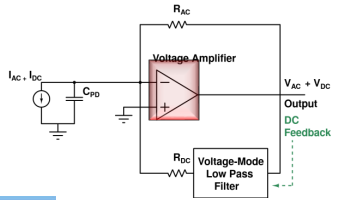


[J.Zhang et al., IEEE Access, Vol.7, 2019]

Radiation-hardened CMOS Design Cycle



RHBD : Radiation Hardening by Design



Current development focus



LISA:

- Tackle noise requirement using suitable architectures and radiation effects study
- Use analysis to implement RHBD techniques to ensure performance reliability



ET- LF:

- Deep-cryogenic characterization to obtain a working compact model
- Use the compact model to design a cryo-CMOS MEMS interface
- In the meantime, design the cryo-MEMS sensor

Conclusion

- ⚙️ Integrated circuits enable compact and low-power implementations of functional blocks
- ⚙️ Appropriate modeling of environmental factors further assists in performance and reliability
- ⚙️ Overall, a customized solution **tailored on the application** that is able to exceed desired performance
- ⚙️ Research in IC domain is typically 15 years ahead of industrial products!

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Thank you for your attention!

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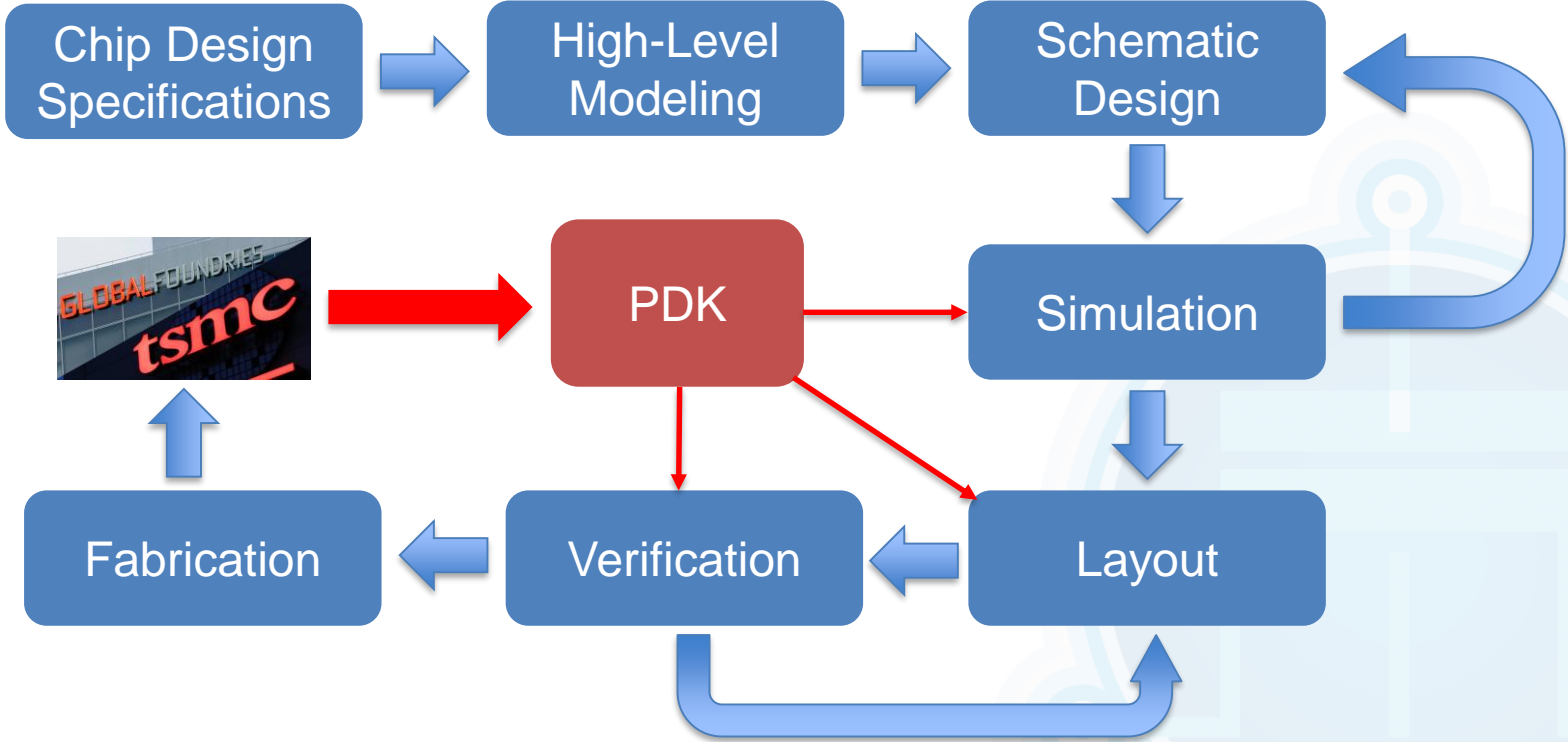


Supplementary slides

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Chip Design Workflow



Process Design Kits (PDKs)

